

Table 3. Refined values of the mosaic spread (full width at half height in seconds of arc) as obtained from monochromatic and TOF neutrons for model Z

	MON	TOF
15 K	3.8 (1)	8.1 (3)
60 K	3.2 (1)	10.2 (3)
295 K	4.0 (1)	12.4 (4)

extinction is pronounced only for few reflections which leads to refined mosaic spreads that are considerably smaller than the experimental estimates. It thus appears that the extinction corrections will be overestimated in least-squares refinements that are based on data sets where only a small part of the reflections are affected by extinction.

The overall counting statistical precision of a data set may be summarized by the statistical R factor, $R_{\text{stat}}(F^2) = \sum \sigma_{\text{cs}}(F^2) / \sum F^2$, which imposes a lower limit to the conventional crystallographic R factor, $R(F^2) = \sum |F_{\text{obs}}^2 - F_{\text{calc}}^2| / \sum F_{\text{obs}}^2$. It is apparent from Table 1 that the TOF data are subject to additional uncertainties besides counting statistics to a higher degree than the monochromatic data. The agreement of the derived results, however, indicates these additional uncertainties to be of a random rather than of a systematic nature.

The purpose behind the measurement of data sets with two methods was to check whether the mean thermal nuclear positions of fluorine differ in the paramagnetic and antiferromagnetically ordered state. Actually, the low temperature of the neutron investigation reported in I as 15 K was about 60 K. We now find that at 15 K, the magnetostrictive shifts

$\Delta x = x(15 \text{ K}) - x(295 \text{ K})$ are $-2.9(4) \times 10^{-4}$ and $-2.7(4) \times 10^{-4}$ using monochromatic and TOF neutrons, respectively. This corresponds to an average shift of $1.95(20) \times 10^{-3} \text{ \AA}$ in the Mn—F distance within the plane normal to the c axis. This shift is different from the result deduced from γ -ray diffraction: $\Delta x = -4.8(7) \times 10^{-4}$. The implications of this subtle difference will be discussed in a forthcoming paper, dealing with the charge density distribution in MnF₂.

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Structures of Na(In,Sc)Si₂O₆ Clinopyroxenes Formed at 6 GPa Pressure

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Abstract

Crystal structures have been refined from single-crystal X-ray data for nine synthetic clinopyroxenes in the system NaInSi₂O₆–NaScSi₂O₆, crystallized at 1770 K and 6 GPa pressure. The structures are isomorphous with other sodium pyroxenes. The space group is $C2/c$, $Z = 4$. In and Sc occupy a distorted octahedral ($M1$) site. The $M1$ — $M1$ dis-

tances and the $M1$ — $O1$ — $M1$ angles correlate with the mean $M1$ — $O1$ distances in such a way as to follow two different trends, suggesting that there are two different electronic states for the octahedral In^{3+} ions. The Si—O distances constitute two populations which can be related to the mean electronegativity of the octahedral ($M1$) ions. From the Si—O distances, the electronegativities of the two In^{3+} ions are 1.2 and 1.7 on Pauling's scale.

Table 1. Crystal data for nine Na(In,Sc)Si₂O₆ clinopyroxenes

	In100	In80Sc20	In65Sc35	In60Sc40	In55Sc45	In50Sc50	In40Sc60A*	In40Sc60	In20Sc80
<i>a</i> (Å)	9.8997 (5)	9.8907 (5)	9.8811 (5)	9.8782 (5)	9.8734 (5)	9.8701 (4)	9.8634 (6)	9.8659 (5)	9.8516 (5)
<i>b</i> (Å)	9.1310 (3)	9.1164 (2)	9.1043 (2)	9.1008 (3)	9.0947 (2)	9.0901 (2)	9.0827 (3)	9.0848 (2)	9.0698 (2)
<i>c</i> (Å)	5.3656 (3)	5.3623 (3)	5.3592 (3)	5.3582 (2)	5.3570 (3)	5.3559 (2)	5.3542 (4)	5.3553 (3)	5.3521 (3)
β (°)	107.226 (2)	107.204 (2)	107.188 (2)	107.191 (2)	107.187 (2)	107.179 (2)	107.174 (3)	107.178 (2)	107.175 (2)
<i>V</i> (Å ³)	463.26 (4)	461.87 (4)	460.59 (4)	460.18 (4)	459.55 (4)	459.10 (3)	458.28 (5)	458.58 (3)	456.90 (3)
<i>M_r</i>	289.98	276.00	265.52	262.03	258.54	255.04	248.06	248.06	234.08
<i>D_x</i> (g cm ⁻³)	4.16	3.97	3.83	3.78	3.74	3.69	3.59	3.59	3.40

* Annealed at 1073 K and atmospheric pressure.

Table 2. Data collection information for nine Na(In,Sc)Si₂O₆ clinopyroxenes

	In100	In80Sc20	In65Sc35	In60Sc40	In55Sc45	In50Sc50	In40Sc60A	In40Sc60	In20Sc80
Size of crystal (mm)	0.13 × 0.06 × 0.08	0.13 × 0.12 × 0.12	0.08 × 0.08 × 0.06	0.11 × 0.08 × 0.04	0.16 × 0.12 × 0.11	0.12 × 0.08 × 0.06	0.12 × 0.12 × 0.12	0.12 × 0.12 × 0.12	0.17 × 0.10 × 0.10
μ (cm ⁻¹)	55.8	49.0	44.0	42.3	40.6	38.9	35.5	35.5	28.6
<i>F</i> (000)	544	521.6	504.8	499.2	493.6	488.0	476.8	476.8	454.4
<i>T</i> (K)	296	297	297	296	296	296	297	298	298
<i>h</i>	0 to 14	0 to 14	0 to 14	0 to 14	0 to 14	0 to 14	0 to 14	0 to 14	0 to 14
<i>k</i>	0 to 13	0 to 13	0 to 13	0 to 13	0 to 13	0 to 13	0 to 13	0 to 13	0 to 13
<i>l</i>	-7 to 7	-7 to 7	-7 to 7	-7 to 7	-7 to 7	-7 to 7	-7 to 7	-7 to 7	-7 to 7
No. of reflections									
Measured	807	805	802	802	801	801	800	800	798
Observed	793	800	776	761	790	767	785	790	781
Used	792	799	774	758	787	759	771	785	780
<i>R</i>	1.671	1.857	1.654	2.011	1.887	2.351	1.839	1.818	1.938
<i>wR</i>	3.745	4.641	3.158	3.172	5.128	4.351	4.344	4.255	5.560
<i>S</i>	1.674	2.146	1.370	1.368	2.330	1.894	1.977	1.933	2.490
($\Delta\rho$) _{max} (e Å ⁻³)	0.719	0.851	0.834	0.749	0.700	0.824	0.618	0.605	0.585
($\Delta\rho$) _{min} (e Å ⁻³)	-0.652	-1.243	-0.841	-1.458	-1.027	-0.991	-0.695	-0.889	-1.210

Introduction

The dependence of Si—O distance on the size and electronegativity of the octahedral M^{3+} ion was examined for the Na M^{3+} Si₂O₆ pyroxenes by Ohashi (1979, 1981, 1983) and Ohashi, Fujita & Osawa (1982, 1983). The Si—O distances correlate with the electronegativities of the octahedral (*M1*) ions in such a way that they follow two different trends: the Sc—Ti—V—Cr—Al series and the In—Fe—Ga series. In the former, the octahedral (*M1*) sites are occupied by lower electron density ions, whereas in the latter the octahedral (*M1*) sites are occupied by higher electron density ions. To study the role of the mean electron density of the octahedral (*M1*) ions, the crystal structures have been refined for nine synthetic clinopyroxenes in the system NaInSi₂O₆–NaScSi₂O₆.

Experimental

All the crystals were synthesized by solid-state reaction using a belt-type high-pressure apparatus (Fukunaga, Yamaoka, Endo, Akaishi & Kanda, 1979). Mixtures of crystalline Na₂Si₂O₅, In₂O₃, Sc₂O₃ and SiO₂ were sealed in platinum capsules and maintained at 1770 K and 6 GPa for 20 h. Unit-cell dimensions of the resulting clinopyroxenes were determined from 2θ values of 25 reflections in the range $55 < 2\theta < 65^\circ$, measured on a four-circle diffractometer with Mo $K\alpha_1$ ($\lambda = 0.70930$ Å) (Table 1). The chemical compositions of the pyroxenes were

determined by microprobe analysis using NaInSi₂O₆ pyroxene and Sc₂Si₂O₇ thortveitite as standards, and by interpolation of the unit-cell dimensions. After the intensity data collection, Na(In_{0.40}Sc_{0.60})Si₂O₆ pyroxene was annealed by heating at 1073 K and atmospheric pressure for 70 h, and intensity data were recollected; this pyroxene is labelled In40Sc60A in the tables.*

The intensity measurements at room temperature were made with an Enraf–Nonius CAD-4 diffractometer using graphite-monochromatized Mo $K\alpha$ ($\lambda = 0.71073$ Å) radiation. Information on data collection is summarized in Table 2. The intensities of the reflections were collected in the range $2\theta < 63^\circ$ using variable-rate ω – 2θ scans with scan range $(0.8 + 0.35\tan\theta)^\circ$. The observed intensities were corrected for Lorentz, polarization and monochromator-polarization factors. No absorption corrections were applied although extinction corrections were made. The least-squares refinements were based on F_o values greater than $3\sigma(F_o)$. The structure refinements were carried out on a MicroVAXII computer, using Enraf–Nonius (1985) *SDP* programs. Initial positional parameters and isotropic displacement factors were those of NaScSi₂O₆ (Hawthorne & Grundy,

* Lists of structure factors, atomic coordinates and anisotropic thermal parameters have been deposited with the British Library Document Supply Centre as Supplementary Publication No. SUP 53425 (54 pp.). Copies may be obtained through The Technical Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

Table 3. Fractional atomic coordinates and equivalent isotropic displacement parameters (Å²) for nine Na(In,Sc)Si₂O₆ clinopyroxenes
$$B_{eq} = (4/3)\sum_i \sum_j \beta_{ij} a_i \cdot a_j$$

	In100	In80Sc20	In65Sc35	In60Sc40	In55Sc45	In50Sc50	In40Sc60A	In40Sc60	In20Sc80
Si	x	0.29172 (7)	0.29162 (7)	0.29162 (5)	0.29152 (6)	0.29153 (6)	0.29145 (5)	0.29135 (4)	0.29117 (5)
	y	0.08660 (6)	0.08661 (6)	0.08678 (5)	0.08680 (5)	0.08682 (6)	0.08684 (6)	0.08692 (5)	0.08695 (4)
	z	0.2475 (1)	0.2472 (1)	0.24646 (9)	0.2463 (1)	0.2461 (1)	0.2460 (1)	0.24583 (8)	0.24575 (8)
O1	B	0.412 (9)	0.395 (8)	0.390 (6)	0.423 (7)	0.345 (7)	0.321 (8)	0.328 (6)	0.343 (5)
	x	0.1190 (2)	0.1191 (2)	0.1190 (1)	0.1188 (1)	0.1190 (1)	0.1188 (2)	0.1189 (1)	0.1193 (1)
	y	0.0797 (2)	0.0792 (2)	0.0789 (1)	0.0790 (1)	0.0789 (1)	0.0789 (2)	0.0789 (1)	0.0794 (1)
O2	z	0.1505 (3)	0.1495 (3)	0.1496 (2)	0.1489 (2)	0.1489 (3)	0.1486 (3)	0.1478 (2)	0.1482 (2)
	B	0.53 (2)	0.53 (2)	0.53 (2)	0.55 (2)	0.51 (2)	0.47 (2)	0.45 (2)	0.45 (2)
	x	0.3568 (2)	0.3570 (1)	0.3577 (1)	0.3576 (1)	0.3577 (2)	0.3581 (2)	0.3583 (1)	0.3583 (1)
O3	y	0.2455 (2)	0.2464 (2)	0.2464 (1)	0.2465 (1)	0.2470 (2)	0.2468 (2)	0.2466 (1)	0.2463 (1)
	z	0.3177 (3)	0.3152 (3)	0.3140 (2)	0.3138 (2)	0.3131 (3)	0.3121 (3)	0.3119 (2)	0.3117 (2)
	B	0.75 (2)	0.74 (2)	0.72 (2)	0.75 (2)	0.70 (2)	0.67 (2)	0.68 (2)	0.70 (2)
M1(In,Sc)	x	0.3488 (1)	0.3491 (1)	0.3494 (1)	0.3494 (1)	0.3500 (1)	0.3497 (1)	0.3497 (1)	0.34975 (9)
	y	0.0115 (2)	0.0111 (2)	0.0107 (1)	0.0105 (2)	0.0101 (2)	0.0100 (2)	0.0096 (2)	0.0093 (1)
	z	0.0172 (3)	0.0182 (3)	0.0186 (2)	0.0182 (2)	0.0186 (2)	0.0187 (2)	0.0177 (2)	0.0180 (2)
M2(Na)	B	0.66 (2)	0.67 (2)	0.63 (2)	0.67 (2)	0.60 (2)	0.57 (2)	0.61 (2)	0.58 (2)
	y	0.89471 (2)	0.89485 (2)	0.89507 (2)	0.89511 (2)	0.89518 (2)	0.89525 (3)	0.89535 (2)	0.89536 (2)
	B	0.417 (4)	0.397 (4)	0.418 (3)	0.413 (3)	0.410 (5)	0.411 (5)	0.377 (4)	0.403 (4)
	y	0.3033 (2)	0.3036 (1)	0.3039 (1)	0.3037 (1)	0.3037 (1)	0.3038 (2)	0.3036 (1)	0.3039 (1)
	B	1.47 (3)	1.40 (2)	1.36 (2)	1.42 (2)	1.35 (2)	1.25 (2)	1.30 (2)	1.33 (2)
									1.27 (2)

Table 4. M1(In,Sc)—O and M1—M1 distances (Å), M1—O1—M1 angles (°), Si—O distances (Å), and Si—O3—Si and O3—O3—O3 angles (°) in Na(In,Sc)Si₂O₆ pyroxenes

	M1—O1A1,B1	M1—O1A2,B2	M1—O2C1,D1	⟨M1—O1⟩	M1—M1	M1—O1—M1		
In100	2.213 (2)	2.136 (1)	2.074 (2)	2.174	3.3007 (1)	98.74 (6)		
In80Sc20	2.209 (2)	2.131 (1)	2.061 (2)	2.170	3.2961 (1)	98.84 (5)		
In65Sc35	2.202 (1)	2.130 (1)	2.053 (1)	2.166	3.2910 (1)	98.88 (4)		
In60Sc40	2.202 (1)	2.126 (1)	2.052 (1)	2.164	3.2898 (2)	98.95 (5)		
In55Sc45	2.199 (2)	2.126 (1)	2.045 (2)	2.163	3.2878 (2)	98.95 (5)		
In50Sc50	2.199 (2)	2.123 (1)	2.042 (2)	2.161	3.2860 (2)	98.96 (6)		
In40Sc60A	2.198 (1)	2.119 (1)	2.040 (1)	2.159	3.2834 (2)	99.01 (4)		
In40Sc60	2.204 (1)	2.122 (1)	2.042 (1)	2.163	3.2840 (2)	98.77 (4)		
In20Sc80	2.191 (1)	2.117 (1)	2.029 (1)	2.154	3.2772 (1)	99.05 (4)		
Sc100*	2.183 (2)	2.105 (5)	2.017 (2)	2.144	3.269 (1)	99.3 (1)		
	Si—O(1)	Si—O(2)	⟨Si—O(nbr)⟩	Si—O(3)	Si—O(3)	⟨Si—O(br)⟩	⟨Si—O⟩	
In100	1.634 (2)	1.587 (2)	1.611	1.653 (2)	1.653 (2)	1.653	1.632	
In80Sc20	1.632 (2)	1.591 (2)	1.612	1.648 (2)	1.655 (1)	1.652	1.632	
In65Sc35	1.631 (1)	1.590 (1)	1.611	1.645 (1)	1.658 (1)	1.652	1.631	
In60Sc40	1.632 (1)	1.590 (1)	1.611	1.648 (1)	1.655 (1)	1.652	1.631	
In55Sc45	1.629 (2)	1.594 (2)	1.612	1.650 (2)	1.656 (1)	1.653	1.632	
In50Sc50	1.630 (2)	1.592 (2)	1.611	1.647 (2)	1.656 (1)	1.651	1.631	
In40Sc60A	1.628 (1)	1.589 (1)	1.609	1.652 (1)	1.651 (1)	1.651	1.630	
In40Sc60	1.623 (1)	1.587 (1)	1.605	1.653 (1)	1.651 (1)	1.652	1.629	
In20Sc80	1.625 (1)	1.590 (1)	1.608	1.649 (1)	1.656 (1)	1.652	1.630	
Sc100*	1.630 (3)	1.592 (2)	1.611	1.653 (2)	1.653 (3)	1.653	1.632	
	Si—O3—Si	O3—O3—O3		Si—O3—Si	O3—O3—O3			
In100	140.84 (10)	171.03 (8)	In50Sc50	140.52 (9)	172.20 (9)			
In80Sc20	140.76 (9)	171.40 (7)	In40Sc60A	140.46 (7)	172.52 (7)			
In65Sc35	140.66 (7)	171.65 (7)	In40Sc60	140.43 (6)	172.79 (6)			
In60Sc40	140.62 (8)	171.86 (7)	In20Sc80	140.32 (7)	173.10 (8)			
In55Sc45	140.31 (9)	172.16 (7)	Sc100*	140.2 (1)	173.6 (1)			

* Hawthorne & Grundy (1973).

1973). The atomic scattering factors (including f' and f'') for neutral atoms were taken from *International Tables for X-ray Crystallography* (1974, Vol. IV).

Final unweighted R and weighted $[1/\sigma(F)]^2 R$ indices are listed in Table 2, all $(\Delta/\sigma)_{\max} = 0.00$, and final parameters are listed in Table 3. The atomic coordinates of the NaInSi₂O₆ pyroxene formed at 6 GPa pressure are in good agreement with those of the NaInSi₂O₆ pyroxene formed at atmospheric pressure (Hawthorne & Grundy, 1974). Bond lengths and angles are listed in Table 4, together with the published values for NaScSi₂O₆ (Hawthorne & Grundy, 1973).

Description and discussion

M1 octahedron

Na(In,Sc)Si₂O₆ pyroxenes are isomorphous with other Na pyroxenes (Clark, Appleman & Papike, 1969). In and Sc occupy a distorted octahedral (M1) site. The variations in the mean M1—O1 (hereafter abbreviated ⟨M1—O1⟩) and M1—M1 distances and the M1—O1—M1 angle with chemical composition are shown in Fig. 1. There are two different trends. The solid circles in the figure represent the extrapolated values for the imaginary NaInSi₂O₆ pyroxene [hereafter abbreviated NaIn(α)-P_x]. The extrapo-

lated values are 2.190 Å for $\langle M1-O1 \rangle$, 3.308 Å for $M1-M1$ and 98.0° for $M1-O1-M1$, respectively. The real $\text{NaInSi}_2\text{O}_6$ pyroxene is hereafter abbreviated to $\text{NaIn}(\beta)\text{-}P_x$.

The variations of $M1-M1$ distance and $M1-O1-M1$ angle with $\langle M1-O1 \rangle$ are shown in Fig. 2; $M1-M1 \approx 2\langle M1-O1 \rangle \sin[(M1-O1-M1)/2]$. The solid circles in the figure represent the estimated values for $\text{NaIn}(\alpha)\text{-}P_x$. Note that there are two different trends: the $\text{Na}[\text{In}(\alpha), \text{Sc}]\text{Si}_2\text{O}_6$ series and the $\text{Na}[\text{In}(\beta), \text{Sc}]\text{Si}_2\text{O}_6$ series.

The pyroxenes used in this study were formed at 6 GPa pressure. However, as mentioned above, the crystal structure of the In100 pyroxene is the same as that of the $\text{NaInSi}_2\text{O}_6$ pyroxene formed at atmospheric pressure. Furthermore, the two polymorphs of the In40Sc60 pyroxene show that the $\text{Na}[\text{In}(\alpha), \text{Sc}]\text{Si}_2\text{O}_6$ pyroxene changes to the $\text{Na}[\text{In}(\beta), \text{Sc}]\text{Si}_2\text{O}_6$ pyroxene by heating at atmospheric pressure. These facts indicate that the $\text{Na}[\text{In}(\alpha), \text{Sc}]\text{Si}_2\text{O}_6$ pyroxene is the high-pressure polymorph and the $\text{Na}[\text{In}(\beta), \text{Sc}]\text{Si}_2\text{O}_6$ pyroxene is the low-pressure polymorph.

The phase transition between the two polymorphs may be caused by the geometrical change of the octahedral site. Since $M1-O1-M1 + O1-M1-O1$

$= 180^\circ$, the two trends in Figs. 1 and 2 imply that the $\text{In}(\alpha)$ ion occupies a less distorted octahedral site, and $\text{In}(\beta)$ ion occupies a more distorted octahedral site.

These physico-chemical and crystal-chemical results suggest that there are two different electronic states (e.g. d^{10} , $d-s$ mixing and/or $d-p$ mixing states) for the octahedral In^{3+} ions, reflecting pressure and chemical conditions.

Si tetrahedron

There are two kinds of bonds in the pyroxene tetrahedron; one is a bridging (br) bond connecting the tetrahedra along the chain, and the other is a nonbridging (nbr) bond, with each tetrahedron having two (br) and two (nbr) bonds. Fig. 3 shows the variations of Si-O3-Si and O3-O3-O3 angles with chemical composition. The Si-O3-Si angle increases with increasing In content, that is, with an increase of the mean radius of the M^{3+} ions. On the other hand, the O3-O3-O3 angle correlates with chemical composition along two different trends: the $\text{Na}[\text{In}(\alpha), \text{Sc}]\text{Si}_2\text{O}_6$ pyroxenes and the $\text{Na}[\text{In}(\beta), \text{Sc}]\text{Si}_2\text{O}_6$ pyroxenes. Fig. 4 shows the variations of $\langle \text{Si-O}(\text{br}) \rangle$ and $\langle \text{Si-O}(\text{nbr}) \rangle$ distances with chemical composition. $\langle \text{Si-O}(\text{br}) \rangle$ does not vary significantly with chemical composition. On the other hand, $\langle \text{Si-O}(\text{nbr}) \rangle$ correlates with chemical composition in two different ways. $\langle \text{Si-O}(\text{nbr}) \rangle$ in $\text{Na}[\text{In}(\alpha), \text{Sc}]\text{Si}_2\text{O}_6$ pyroxene decreases with increasing $\text{In}(\alpha)$ content. By contrast, $\langle \text{Si-O}(\text{nbr}) \rangle$ in $\text{Na}[\text{In}(\beta), \text{Sc}]\text{Si}_2\text{O}_6$ pyroxene does not change with chemical composition.

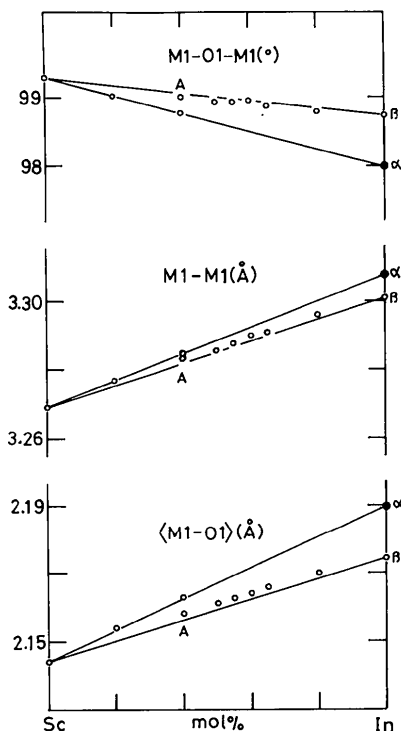


Fig. 1. Variation of $M1-O1-M1$ angle, $M1-M1$ distance and mean $M1-O1$ distance with chemical composition in $\text{Na}(\text{In}, \text{Sc})\text{Si}_2\text{O}_6$ pyroxenes. Solid circles represent the extrapolated values for $\text{NaIn}(\alpha)\text{-}P_x$.

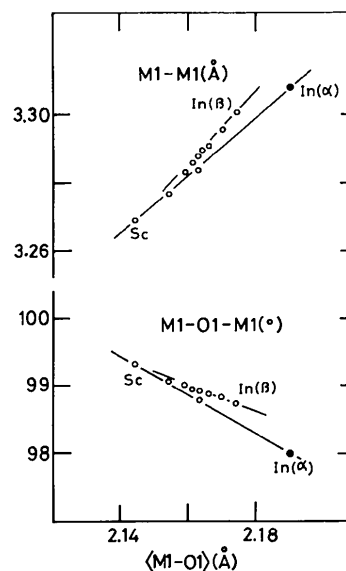


Fig. 2. Variation of $M1-M1$ distance and $M1-O1-M1$ angle with mean $M1-O1$ distance in $\text{Na}(\text{In}, \text{Sc})\text{Si}_2\text{O}_6$ pyroxenes. Solid circles represent the extrapolated values for $\text{NaIn}(\alpha)\text{-}P_x$.

The dependence of Si—O distances on size, electronegativity and electron density of the octahedral M^{3+} ion in $NaM^{3+}Si_2O_6$ pyroxenes was examined by Ohashi (1979, 1981, 1983) and Ohashi, Fujita & Osawa (1982, 1983). Generally, $\langle Si-O \rangle$ increases with an increase in the radius of the M^{3+} ion. In the Sc—Ti—V—Cr—Al series, the size of the M^{3+} ion affects Si—O(br) and Si—O(nbr) equally. On the other hand, in the In—Fe—Ga series, the size of the M^{3+} ion affects only Si—O(br).

Assuming that the $Na[In(\alpha),Sc]Si_2O_6$ pyroxene belongs to the Sc—Al series, the differences, $d_{br-\Delta}$ and $d_{nbr-\Delta}$, are independent of the size of the M^{3+} ion, where $\Delta = \{ \langle Si-O \rangle \text{ in } Na[In(\alpha),Sc]Si_2O_6 \} - \{ \langle Si-O \rangle \text{ in } NaAlSi_2O_6 \}$, $d_{br-\Delta} = \langle Si-O(br) \rangle - \Delta$, and $d_{nbr-\Delta} = \langle Si-O(nbr) \rangle - \Delta$. Δ , $d_{br-\Delta}$ and $d_{nbr-\Delta}$ for the $Na[In(\alpha),Sc]Si_2O_6$ pyroxenes are listed in Table 5 and shown in Fig. 5.

The scaled Si—O(br) distance increases and the scaled Si—O(nbr) distance decreases with an increase

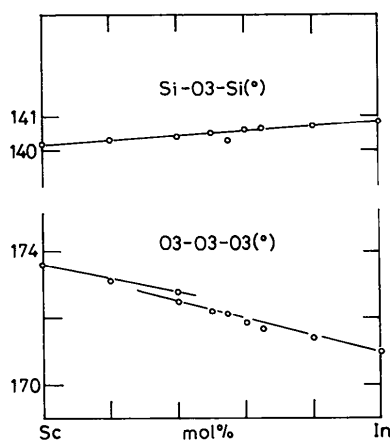


Fig. 3. Variation of Si—O3—Si and O3—O3—O3 angles with chemical composition in $Na(In,Sc)Si_2O_6$ pyroxenes.

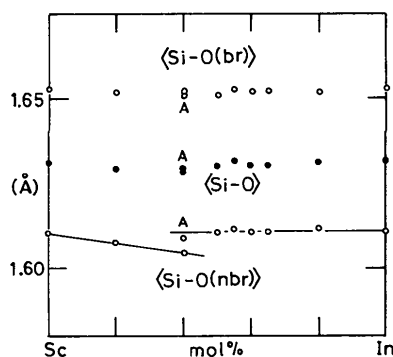


Fig. 4. Si—O distances versus chemical composition in $Na(In,Sc)Si_2O_6$ pyroxenes. Open circles represent $\langle Si-O(br) \rangle$ and $\langle Si-O(nbr) \rangle$ distances; solid circles represent $\langle Si-O \rangle$ distances.

Table 5. The differences (\AA), Δ , $d_{br-\Delta}$, $d_{nbr-\Delta}$ and $d_{br-2\Delta}$, in $Na(In,Sc)Si_2O_6$ pyroxenes and the mean electronegativity (χ) of the octahedral ions

	Δ^*	$d_{br-\Delta}$	$d_{nbr-\Delta}$	$d_{br-2\Delta}$	χ
In100	0.009			1.635	1.7
In80Sc20	0.009			1.634	1.62
In65Sc35	0.008			1.636	1.56
In60Sc40	0.008			1.636	1.54
In55Sc45	0.009			1.635	1.508
In50Sc50	0.008			1.635	1.484
In40Sc60A	0.007			1.637	1.46
In(α)100		1.651†	1.595†		1.18†
In40Sc60	0.006	1.646	1.599		1.252
In20Sc80	0.007	1.645	1.601		1.276
Sc100	0.009	1.644	1.602		1.3

* $\Delta = \langle Si-O \rangle - 1.623$ (\AA).
† Extrapolated values.

in the $NaIn(\alpha)Si_2O_6$ component, suggesting that the $In(\alpha)^{3+}$ ion is more electropositive than the Sc^{3+} ion. These changes may be accompanied by expansion of the Si orbitals and by an increase in the π bonding between Si and O(nbr). The solid circles in the figure represent the extrapolated values for $NaIn(\alpha)-P_x$. The extrapolated values are 1.651 \AA for $d_{br-\Delta}$ and 1.595 \AA for $d_{nbr-\Delta}$.

On the other hand, Si—O distances in $Na[In(\beta),Sc]Si_2O_6$ pyroxenes do not change with composition (Fig. 4). Assuming that $In(\beta)-P_x$ belongs to the In—Ga series, the difference, $d_{br-2\Delta}$, and the mean Si—O(nbr) distance are independent of the size of the M^{3+} ion, where $d_{br-2\Delta} = \langle Si-O(br) \rangle - 2\Delta$. Δ and $d_{br-2\Delta}$ are listed in Table 5 and are shown in Fig. 5. In the $Na[In(\beta),Sc]Si_2O_6$ pyroxenes, $\langle Si-O \rangle$ and the scaled Si—O distances do not change with composition, suggesting that they do not depend on the mean electronegativity of the octahedral ions.

Fig. 6 and Table 6 show the variation of scaled Si—O distance with the electronegativity of the octahedral M^{3+} ion. The solid circles in the figure represent the scaled and extrapolated Si—O distances for the $Na[In(\alpha),Sc]Si_2O_6$ pyroxenes. Assuming that

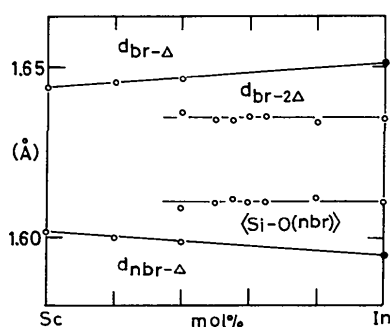


Fig. 5. The differences, $d_{br-\Delta}$, $d_{nbr-\Delta}$ and $d_{br-2\Delta}$, and $\langle Si-O(nbr) \rangle$ distances versus chemical composition in $Na(In,Sc)Si_2O_6$ pyroxenes. Solid circles represent the extrapolated values for $NaIn(\alpha)-P_x$.

Na[In(α),Sc]Si₂O₆ pyroxene belongs to the Sc–Al series, the electronegativity of the In(α) is estimated as 1.18 on Pauling's scale.

Ionic radius and electronegativity of indium

The $\langle M^{3+}-O \rangle$ distance in $NaM^{3+}Si_2O_6$ pyroxene is represented by the equation $\langle M^{3+}-O \rangle = 0.815r_{M^{3+}} + 1.496$ (Å), where $r_{M^{3+}}$ is the effective radius of the M^{3+} ion (Ribbe & Prunier, 1977). The $\langle In-O \rangle$ distance in NaIn(α)Si₂O₆ pyroxene is estimated as 2.153 Å from the $\langle (In,Sc)-O \rangle$ distances in Na[In(α),Sc]Si₂O₆ pyroxenes, and the $\langle In-O \rangle$ distance in NaIn(β)Si₂O₆ pyroxene is 2.141 Å. Therefore, the effective ionic radii of In(α) and (β) are 0.805 and 0.791 Å, respectively. These values are nearly the same as the effective ionic radius ($r = 0.80$ Å) (Shannon, 1976).

On the other hand, there is considerable variation in the electronegativities of the octahedral In³⁺ ions. The electronegativities of In(α) and (β) are estimated as 1.18 and 1.7, respectively. The former is unusually electropositive, and the latter is coincident with the electronegativity calculated from the heat of formation of indium halides (Pauling, 1960; Ohashi, 1987). These variations may be caused by the different electronic structures (e.g. d^{10} , $d-s$ mixing and $d-p$ mixing states) mentioned above.

The Na(In,Sc)Si₂O₆ pyroxenes used in this study were formed at 6 GPa pressure. However, as mentioned above, In(α) is the high-pressure-type ion and In(β) is the low-pressure-type ion. At high pressure, the In–O distance is short and the crystal field is strong. Therefore, it is expected that the outer ten

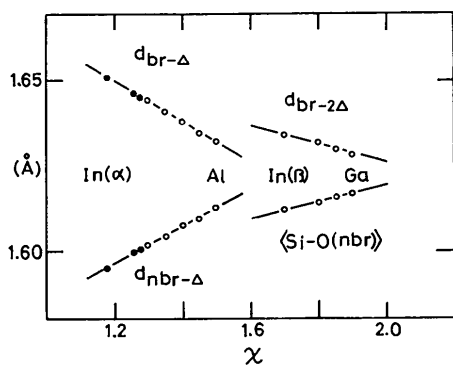


Fig. 6. The differences, $d_{br-\Delta}$, $d_{n_{br-\Delta}}$ and $d_{br-2\Delta}$, and $\langle Si-O(nbr) \rangle$ distance versus electronegativity (χ) of the M^{3+} ion for $NaM^{3+}Si_2O_6$ pyroxenes. Solid circles represent the scaled and extrapolated Si–O distances for Na[In(α),Sc]Si₂O₆ pyroxenes.

Table 6. The differences (Å), Δ , $d_{br-\Delta}$, $d_{n_{br-\Delta}}$ and $d_{br-2\Delta}$, and $\langle Si-O(nbr) \rangle$ distances (Å) in $NaM^{3+}Si_2O_6$ pyroxenes and the electronegativities (χ) of the M^{3+} ions

The electronegativities in parentheses are the estimated values; other values from Pauling (1960).

M^{3+}	Δ^*	$d_{br-\Delta}$	$d_{n_{br-\Delta}}$	$d_{br-2\Delta}$	$\langle Si-O(nbr) \rangle$	χ	Ref.
Sc	0.009	1.644	1.602			1.3	(a)
Cr	0.001	1.641	1.605			(1.35)†	(b)
V	0.001	1.638	1.608			(1.4)†	(a)
Ti	0.004	1.635	1.610			(1.45)†	(c)
Al	0	1.632	1.613			1.5	(a)
In(β)	0.009			1.634	1.612	1.7	(a)
Fe	0.005			1.632	1.614	1.8	(a)
Mn	0.008			1.630	1.616	(1.85)†	(d)
Ga	0.003			1.628	1.617	(1.9)	(e)

References: (a) Ohashi (1981); (b) Ohashi (1983); (c) Ohashi, Fujita & Osawa (1982); (d) Ohashi, Osawa & Tsukimura (1987); (e) Ohashi, Fujita & Osawa (1983).

* Δ is equal to $\langle Si-O \rangle - 1.623$ (Å).

† These values are changeable and increase with an increase in the regularity of the octahedral site (e.g. Cr changes from 1.35 to 1.55).

electrons will occupy the $4d$ orbitals and the screening constant for the d^{10} state will be higher than those for the $d-s$ and/or $d-p$ mixing states. Thus the unusual electropositive character of In(α) may be caused by the high screening constant for the d^{10} state.

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